



Ref. Certif. No.

DE 3 - 30756

IEC SYSTEM FOR MUTUAL RECOGNITION OF TEST CERTIFICATES FOR ELECTRICAL EQUIPMENT (IECEE) CB SCHEME

SYSTEME CEI D'ACCEPTATION MUTUELLE DE CERTIFICATS D'ESSAIS DES EQUIPEMENTS ELECTRIQUES (IECEE) METHODE OC

CB TEST CERTIFICATE CERTIFICAT D'ESSAI OC

Product

Microscopes
(IVD equipment)

Name and address of the applicant

Leica Microsystems CMS GmbH
Ernst-Leitz-Straße 17-37
35578 Wetzlar
GERMANY

Name and address of the manufacturer

Leica Microsystems CMS GmbH
Ernst-Leitz-Straße 17-37, 35578 Wetzlar, GERMANY

Name and address of the factory

Leica Microsystems Ltd. Shanghai
Building 1, 258 Jinzang Road, China (Shanghai) Pilot Free Trade,
201206 Shanghai, PEOPLE'S REPUBLIC OF CHINA

Ratings and principal characteristics

Rated Voltage: 100-240 VAC
Rated frequency: 50/60 Hz
Rated power: 18 VA
Protection class: I
Lamp classification group: exempt group

Trade mark (if any)

Leica

Model/type Ref.

DMi1

Additional information (if necessary)

Certificate DE 3 - 3999 issued 2015-05-12 is replaced by this version due to technical changes

A sample of the product was tested and found to be in conformity with

IEC 61010-1:2010
IEC 61010-2-101:2015

as shown in the Test Report Ref. No. which forms part of this certificate

028-713137139-000

This CB Test Certificate is issued by the National Certification Body
Ce Certificat d'essai OC est établi par l'Organisme **National de Certification**

CB 056257 0193 Rev. 00

Date, 2018-07-19



Page 1 of 1

(Ralph Fischer)

Product Service

TÜV SÜD Product Service GmbH • Certification Body • Ridlerstraße 65 • 80339 Munich • Germany